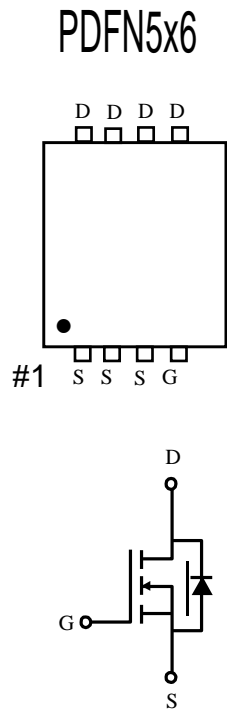


N-Channel High Density Trench MOSFET

FEATURES

- Super high dense cell trench design for low $R_{DS(on)}$.
- Rugged and reliable.
- Surface Mount package.

PRODUCT SUMMARY		
$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
100V	8mΩ	60A



ABSOLUTE MAXIMUM RATINGS ($T_A = 25\text{ }^\circ\text{C}$ unless otherwise noted)

PARAMETERS TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source voltage		V_{GS}	± 20	V
Continuous Drain current	$T_C = 25\text{ }^\circ\text{C}$	I_D	60	A
	$T_C = 100\text{ }^\circ\text{C}$		39	
Pulsed Drain Current ¹		I_{DM}	160	
Avalanche Current		I_{AS}	15	
Avalanche Energy	$L=0.1\text{mH}$	E_{AS}	33	mJ
Power Dissipation	$T_C = 25\text{ }^\circ\text{C}$	P_D	56.5	W
	$T_C = 100\text{ }^\circ\text{C}$		35	
Operating junction & Storage Temperature Range		T_s, T_{stg}	-55 to 150	$^\circ\text{C}$

THERMAL CHARACTERISTICS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta Jc}$		2.2	$^\circ\text{C/W}$
Junction-to-Ambient	$R_{\theta JA}$		50	$^\circ\text{C/W}$

ELECTRICAL CHARACTERISTICS (T_A = 25 °C unless otherwise noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} =0V, I _D =250μA	100			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	2	3	4	
Gate-Body Leakage	I _{GSS}	V _{DS} =0V, V _{GS} =± 20V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =80V, V _{GS} =0 V			1	μA
		V _{DS} =80V, V _{GS} =0V, T _J =55°C			5	
Drain-Source On- State Resistance ¹	R _{DS(ON)}	V _{GS} =10V, I _D =20A		8	11.5	mΩ
Forward Trans conductance ¹	g _{fs}	V _{DS} =5V, I _D =20A		36		S

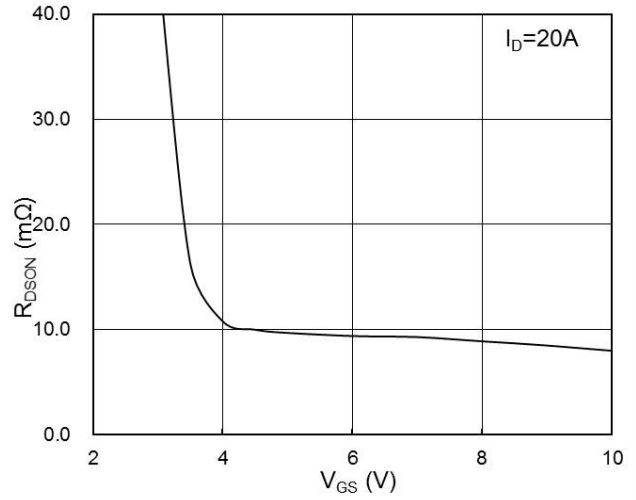
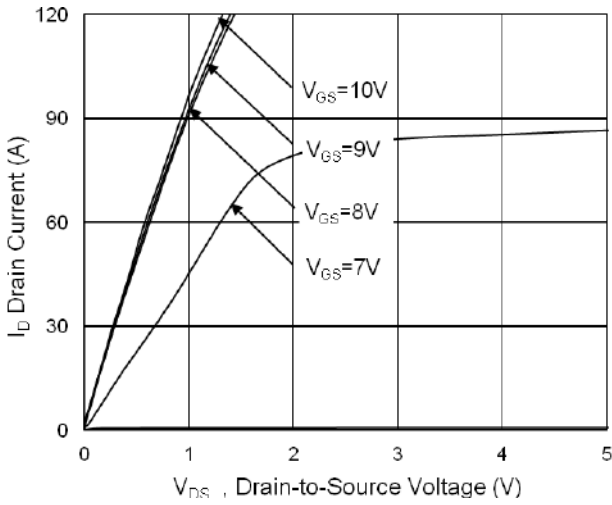
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} =0V, V _{DS} =50V, f=1MHz		2422		pF
Output Capacitance	C _{oss}			288		
Reverse Transfer Capacitance	C _{rss}			12		
Gate Resistance	R _G	V _{GS} =0V, f=1MHz		3.3		Ω
Total Gate Charge ²	Q _{g(vgs=10V)}	V _{DS} =50V _{(BR)DSS} , V _{GS} =10V I _D = 20A		26		nC
	Q _{g(vgs=4.5V)}			12		
Gate Source Charge ²	Q _{gS(VGS=10V)}			5.5		
Gate-Drain Charge ²	Q _{gd(VGS=10V)}			5		
Turn-On Delay Time ²	t _{d(on)}	V _{DS} =50V, I _D =20A, V _{GS} =10V, R _{GS} =3.3Ω		10		nS
Rise Time ²	t _r			6.5		
Turn-Off Delay Time ²	t _{d(off)}			45		
Fall Time ²	t _f			7.5		

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS(T_J=25°C)

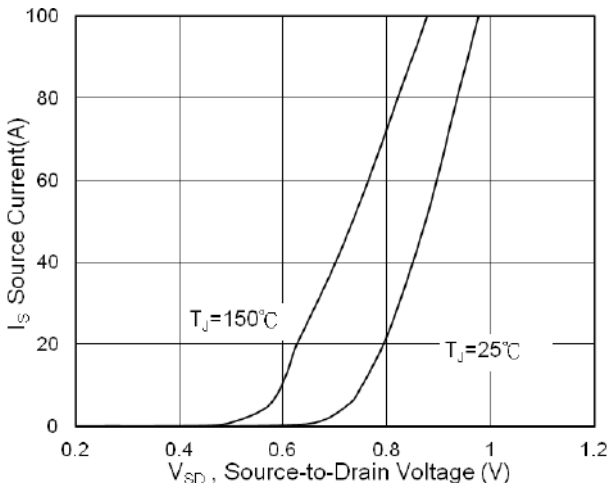
Continuous Current	I _S				35	A
Forward Voltage ¹	V _{SD}	I _F =I _S , V _{GS} =0V		0.75	1.2	V
Reverse Recovery Time	T _{rr}	I _F =20A, dI _F /dt=100A/μs		40		nS
Reverse Recovery Charge	Q _{rr}	I _F =20A, dI _F /dt=100A/μs		162		nC

Note
 b. Pulse Test Pulse width ≤ 300usec , Duty Cycle ≤ 2% .
 c. Independent of operating production testing .

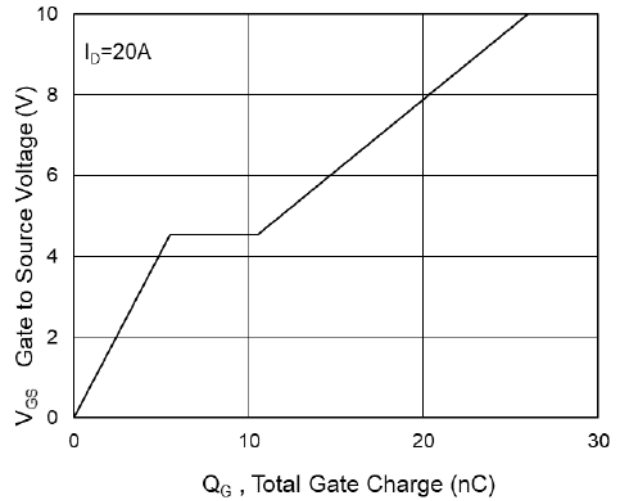
Typical Characteristics



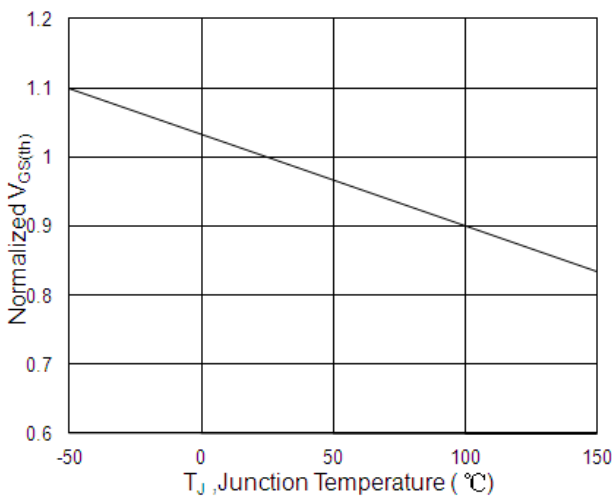
Typical Output Characteristics



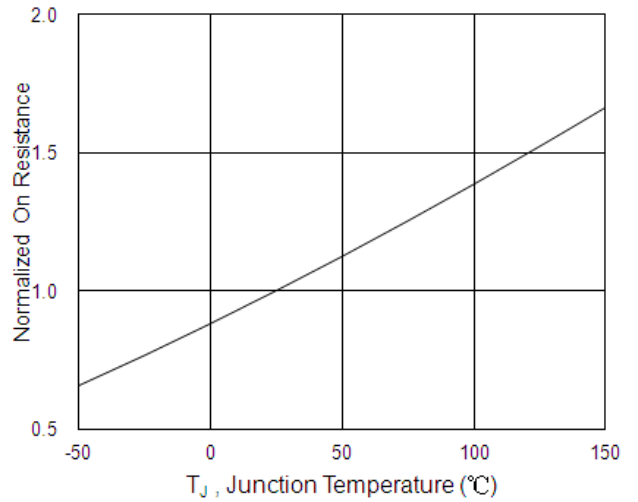
On-Resistance vs G-S Voltage



Source Drain Forward Characteristics

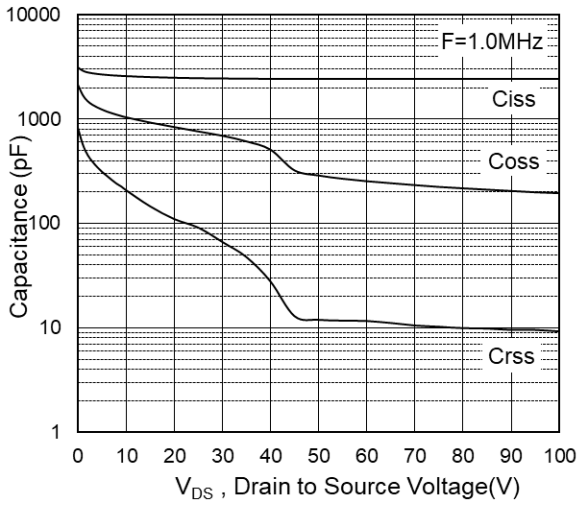


Gate-Charge Characteristics

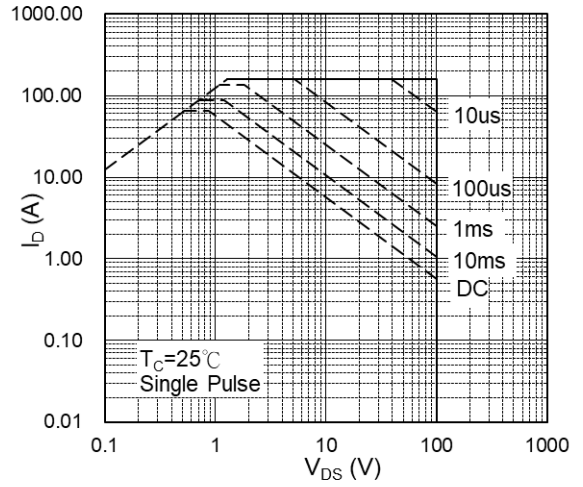


Normalized $V_{GS(th)}$ vs T_J

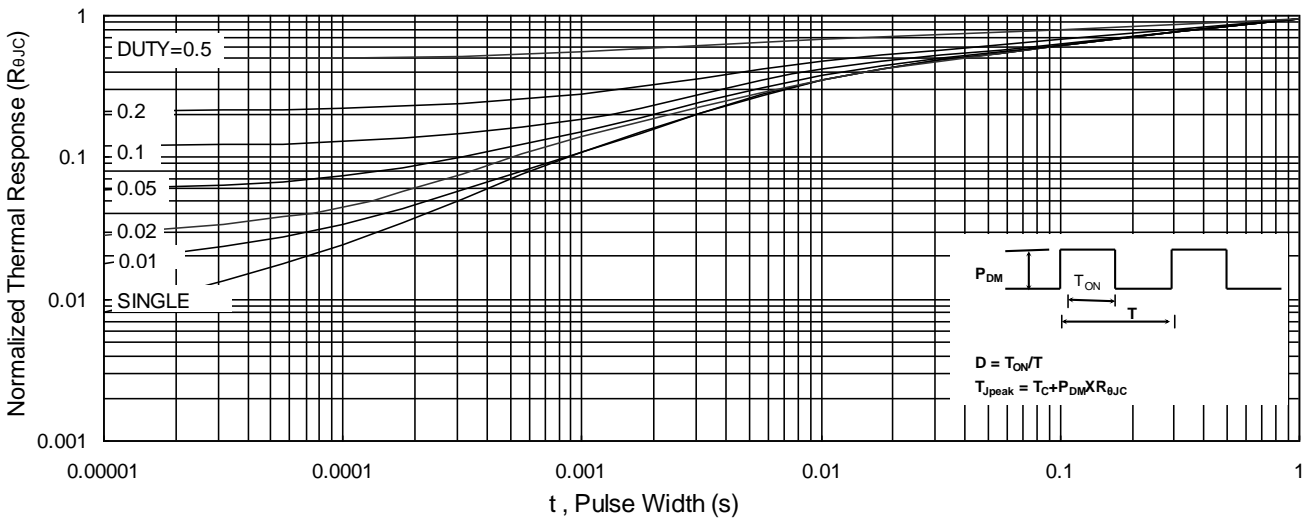
Normalized $R_{DS(on)}$ vs T_J



Capacitance



Safe Operating Area



Normalized Maximum Transient Thermal Impedance